

Notice of References Cited	Application/Control No. 10/677,299		Applicant(s)/Patent Under Reexamination HEO ET AL.	
	Examiner Erin M. File		Art Unit 2611	Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-4,057,834 A	11-1977	Nakagome et al.	358/426.12
*	B	US-2002/0015438 A1	02-2002	Ishizu et al.	375/147
*	C	US-6,430,214 B1	08-2002	Jalloul et al.	375/147
*	D	US-2002/0159507 A1	10-2002	Flaig et al.	375/148
*	E	US-2002/0177432 A1	11-2002	Casaccia et al.	455/410
*	F	US-2003/0022636 A1	01-2003	Ylitalo et al.	455/101
*	G	US-2003/0053524 A1	03-2003	Dent, Paul W.	375/148
*	H	US-2003/0157897 A1	08-2003	Maeda et al.	455/67.3
*	I	US-2004/0028121 A1	02-2004	Fitton, Michael P.	375/144
*	J	US-6,788,733 B1	09-2004	Whang et al.	375/148
*	K	US-2004/0202151 A1	10-2004	Reznik et al.	370/352
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.